- 8-Bit Parallel-Out Storage Register Performs Serial-to-Parallel Conversion with Storage
- Asynchronous Parallel Clear
- Active High Decoder
- Enable/Disable Input Simplified Expansion
- Expandable for N-Bit Applications
- Four District Functional Modes
- Package Options Include Ceramic Chip Carriers and Flat Packages in Addition to Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

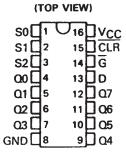
description

These 8-bit addressable latches are designed for general purpose storage applications in digital systems. Specific uses include working registers, serial-holding registers, and active-high decoders or demultiplexers. They are multifunctional devices capable of storing single-line data in eight addressable latches, and being a 1-of-8 decoder or demultiplexer with active-high outputs.

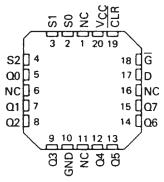
Four distinct modes of operation are selectable by controlling the clear (CLR) and enable (G) inputs as enumerated in the function table. In the addressable-latch mode, data at the data-in terminal is written into the addressed latch. The addressed latch will follow the data input with all unaddressed latches remaining in their previous states. In the memory mode, all latches remain in their previous states and are unaffected by the data or address inputs. To eliminate the possiblity of entering erroneous data in the latches, enable G should be held high (inactive) while the address lines are changing. In the 1-of-8 decoding or demultiplexing mode, the addressed output will follow the level of the D input with all other outputs low. In the clear mode, all outputs are low and unaffected by the address and data inputs.

The SN54259 and SN54LS259B are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74259 and SN74LS259B are characterized for operation from 0°C to 70°C.

SN54259, SN54LS259B . . . J OR W PACKAGE SN74259 . . . N PACKAGE SN74LS259B . . . D OR N PACKAGE

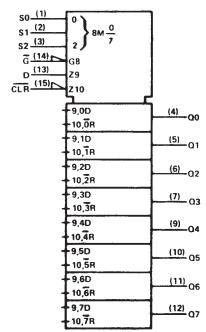


SN54LS259B . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

logic symbol†



[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.



FUNCTION TABLE

INPUT	s G	OUTPUT OF ADDRESSED	EACH OTHER	FUNCTION
		LATCH	OUTPUT	
Н	L	D	Q _{iO}	Addressable Latch
н	Н	Q _{iO}	Q _{i0}	Memory
L	L.	D	L	8-Line Demultiplexer
L	Н	L	L	Clear

 $H \equiv high\ level,\ L \equiv low\ level$

LATCH SELECTION TABLE

SEI	ECT II	SELECT INPUTS					
S2	S1	SO	ADDRESSED				
L	L	L	0				
L	L	H	1				
L	Н	L	2				
L	Н	Н	3				
Н	L	L	4				
Н	L	н	5				
Н	Н	L	6				
Н	Н	н	7				

schematic of inputs and outputs 259

EQUIVALENT OF EACH INPUT

VCC

Req

INPUT

G: Req = 2.2 kΩ NOM

All other inputs: Req = 4 kΩ NOM

TYPICAL OF ALL OUTPUTS

VCC

100 Ω NOM

OUTPUT

TES259B

TES259B

TES259B

TES259B

TES259B

TES259B

TYPICAL OF ALL OUTPUTS

VCC

TYPICAL OF ALL OUTPUTS

VCC

TYPICAL OF ALL OUTPUTS

TYPICAL OF ALL OUTPUTS

VCC

TYPICAL OF ALL OUTPUTS

OUTPUT

OUTPUT

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage (see Note 1)			7 V
Input voltage: SN54259, SN74259			5.5 V
Operating free-air temperature range:	SN54259, SN54LS259B	1	-55° C to 125° C
	SN74259, SN74LS259B	}	0°C to 70°C
Storage temperature range	· · · · · · · · · · · · · · · · · · ·		-65° C to 150° C

NOTE 1: Voltage values are with respect to network ground terminal.



D ≡ the level at the data input

 $[\]alpha_{i0} \equiv$ the level of α_i (i = 0, 1, . . . 7, as appropriate) before the indicated steady-state input conditions were established.

recommended operating conditions

		SN54	259	SN742	SN74259		
		MIN NO	M MAX	MIN NO	1 MAX	UNIT	
Supply voltage, V _{CC}		4.5	5 5.5	4.75	5.25	V	
High-level output current, IOH			-800		800	μΑ	
Low-level output current, IOL			16		16	mA	
Width of clear or enable pulse, tw		15		15		ns	
C	Data	151		151			
Setup time, t _{su}	Address	5†		5↑		ns	
11.11.	Data	0↑		01]	
Hold time, th	Address	20†		20↑		ns	
Operating free-air temperature, T	\	-55	125	0	70	°C	

[†]The arrow indicates that the rising edge of the enable pulse is used for reference.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		7567.00	NDITIONS†	SN54259		9	SN74259			UNIT	
		1EST CC	MUITIONS.	MIN	MIN TYP! MAX		MIN	TYP‡	MAX	UNIT	
ViH	High-level input voltag	je			2			2			V
VIL	Low-level input voltag	e					0.8			8.0	V
VIK	Input clamp voltage		V _{CC} = MIN,	I _I = 12 mA			-1.5			-1.5	V
Voн	High-level output voltage		V _{CC} = MIN, V _{IL} = 0.8 V,	V _{IH} = 2 V, I _{OH} = -800 μA	2.4	3.4		2.4	3.4		V
VOL	Low-level output voltage		V _{CC} = MIN, V _{IL} = 0.8 V,	V _{IH} = 2 V, I _{OL} = 16 mA		0.2	0.4		0.2	0.4	v
11	Input current at maximum input voltage		V _{CC} = MAX,	V ₁ = 5.5 V			1			1	mA
ЧН	High-level input current	G Other inputs	V _{CC} = MAX,	V ₁ = 2.4 V			80 40			80 40	μА
IIL	Low-level input	G Other inputs	V _{CC} = MAX,	V ₁ = 0.4 V			-3.2 -1.6			-3.2 -1.6	mA
1 _{OS}	Short-circuit output current§		V _{CC} = MAX		-18		-57	-18		-57	mA
ICC	Supply current	<u> </u>	V _{CC} = MAX,	See Note 2		60	90		60	90	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, VCC = 5 V, TA = 25°C

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
^t PHL	CLR	Any Q			16	25	ns
tPLH	0		1		14	24	
^t PHL	Data	Any Q	C _L = 15 pF, R _L = 400 Ω, See Note 3		11	20	ns
^t PLH					15	28	ns
tPHL	Address	Any Q			17	28	7 "
[†] PLH	_				12	20	1
tPHL	Ğ	Any Q			11	20	ns

t_{PLH} = propagation delay time, low-to-high-level output

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



 $[\]ddagger$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_{A} = 25^{\circ}\text{C}$.

[§] Not more than one output should be shorted at a time,

NOTE 2: $I_{\mbox{\footnotesize{CC}}}$ is measured with the inputs grounded and the outputs open.

tpHL = propagation delay time, high-to-low-level output

recommended operating conditions

			SN	SN54LS259B			SN74LS259B		
			MIN	NOM	MAX	MIN NOM MAX		UNIT	
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	٧
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7			0.8	V
ЮН	High-level output current				- 0.4			- 0.4	mA
IOL	Low-level output current				4			8	mA
	Dulas dusarias	G low	17			17			
t _W	Pulse duration	CLR low	10			10			. ns
		Data before G †	20			20			
t _{su}	Set up time	Address before G†	17			17			ns
		Address before G↓	0			0			
		Data after G t	0			0			
th	Hold time	Address after G f	0			0			ns
TA	Operating free-air temperature		- 55		125	0		70	°c

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†			SN54LS259B			SN74LS259B				
FANAMETER		1EST COM	Dilions.		MIN TYP MAX			MIN	TYP	MAX	UNIT
VIK	V _{CC} = MIN,	I _I = - 18 mA					1.5			- 1.5	V
Vон	V _{CC} = MIN, I _{OH} = - 0.4 m	V _{IH} = 2 V, A	VIL = MAX,		2.5	3.4		2.7	3.4		V
\/-	V _{CC} = MIN,	V _{IH} = 2 V,		IOL = 4 mA		0.25	0.4		0.25	0.4	v
VOL	VIL = MAX			IOL = 8 mA					0.35	0.5	1 °
l ₁	V _{CC} = MAX,	V _I = 7 V					0.1			0.1	mA
Чн	V _{CC} = MAX,	V ₁ = 2.7 V					20			20	μА
IIL	V _{CC} = MAX,	V _I = 0.4 V				-	- 0.4			- 0.4	mA
los§	V _{CC} = MAX				- 20		- 100	- 20		- 100	mA
lcc	V _{CC} = MAX,	See Note 2			<u> </u>	27	36	· 	22	36	mA

 $^{^\}dagger$ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN TYP	MAX	UNIT
tPHL	CLR	Any Q		12	18	ns
^t PLH	Data	ata Any Q		19	30	
^t PHL	Data		C. = 15 × 5	13	20	ns
^t PLH	Address	Any 0	$C_L = 15 pF$, $R_L = 2 k\Omega$, See Note 3	17	27	
^t PHL	Address	Any Q	See Note 3	14	20	ns
tPLH	Ğ	Any Q		15	24	
^t PHL	3	Any Q		15	24	ns

tpLH = propagation delay time, low-to-high-level output

tpHL = propagation delay time, high-to-low-level output

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



[‡]All typical values are at V_{CC} = 5 V, T_A = 25°C.

 $[\]S$ Not more than one output should be shorted at a time, and duration short-circuit should not exceed one second.

NOTE 2: $I_{\mbox{\footnotesize{CC}}}$ is measured with the inputs grounded and the outputs open.

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1999, Texas Instruments Incorporated